



CALL FOR PAPERS
Testing: Academic and Industrial Conference on Practice and Research Techniques
(TAIC PART 2013)

<http://www.taicpart.org/>

March 18, 2013

Luxembourg

Co-located with IEEE International Conference on Software Testing, Verification and Validation (ICST 2013)

Important Dates

- Paper submission: January 6, 2013
- Fast abstract submission: January 15, 2013
- Author notification: February 8, 2013
- Camera-ready version due: February 28, 2013
- Conference date: March 18, 2013

Theme and Goals

TAIC PART is a workshop that aims to forge collaboration between industry and academia on the challenging and exciting problem of real-world software testing. It is promoted by representatives of both industry and academia, bringing together industrial software engineers and testers with researchers working on theory and practice of software testing. TAIC PART expects submissions relevant to practice and research like evaluation of testing approaches by means of industrial surveys, case studies or experiments, experience reports on the application of scientific approaches in industry, or ideas on how to facilitate the knowledge transfer between industry and academia. The goals of TAIC PART range from the articulation of research questions in the field of software testing and analysis to practical challenges faced in industry. One aim is also to describe and discuss methods for better collaboration between academia and industry in these areas.

Special Features

TAIC PART 2013 offers a **mentoring program** providing prospective submitters the opportunity to obtain advice on a prospective submission. To foster feedback, discussion and cooperation between practitioners and researchers a special **information exchange session** will be organized.

Topics of Interest

TAIC PART 2013 solicits papers within software testing, verification and validation of the following types:

- **Industry experience reports** - provide practical and generalizable insights into how to apply and extend existing approaches to software testing and analysis
 - **Research methods for collaborative research** - describe ways that industry and academia can collaborate to further knowledge on testing, verification and validation
 - **Industrial challenges with real-world testing** - describe a real-world software testing problem for which industry seeks help from academia or vice versa
 - **Knowledge exchange between industry and academia** - how can new results and knowledge be exchanged and transferred between the two partners
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Paper Formatting

We invite submission of papers of the following types:

- Papers (6 pages): Experience reports, research methods, longer challenge papers
- Fast Abstracts (2 pages): work in progress, challenges, positions

Submission and Proceedings

Authors should submit a PDF version of their paper through the TAIC PART 2013 paper submission site. Papers must be written in English and conform to the IEEE Format and Submission Guidelines. For details see the conference web site. All papers will undergo a rigorous review by at least three members of the program committee. All accepted papers will be part of the proceedings. Proceedings will be published in the IEEE Digital Library.

Organization

Conference Chair

Vladimir Entin, Omicron Electronics GmbH, Austria

Program Co-Chairs

Sigrid Eldh, Ericsson AB & Karlstad University, Sweden

Michael Felderer, University of Innsbruck, Austria

Local Arrangements and Publicity Chair

Nadia Alshahwan, University of Luxembourg, Luxembourg

Program Committee

Kelly Androutopoulos, University College London, UK

Andrea Arcuri, Simula Research Laboratory, Norway

Jeremy Bradbury, University of Ontario Institute of Technology, Canada

Robert Feldt, Chalmers University, Sweden

Mark Harman, University College London, UK

Moonzoo Kim, KAIST, Republic of Korea

Jason Lee, Dolby Laboratories, USA

Bruno Legiard, University of Franche-Comte, France

Wassim Masri, American University of Beirut, Lebanon

Atif Memon, University of Maryland, USA

Stefan Mohacsi, Atos, Austria

Robert Nilsson, Google, Switzerland

Per Runeson, Lund University, Sweden

Ina Schieferdecker, FU Berlin, Germany

Saurabh Sinha, IBM Research, India

Harry Sneed, ANECON, Austria

Sebastian Siegl, Audi Electronics Venture, Germany

Matt Staats, KAIST, Republic of Korea

Tanja Vos, Universidad Politécnic de Valencia, Spain

Neil Walkinshaw, University of Leicester, UK

Joachim Wegener, Berner & Mattner, Germany

Carsten Weise, IVU Traffic Technologies AG, Germany

Justyna Zander, SimulatedWay, Germany
